98-2 Preliminary Syllabus, Da-Yeh Univ

Information			
Title	X光繞射與奈米結構分析	Serial No. / ID	2219 / EGR5289
Dept.	電機工程學系碩士班	School System / Class	研究所碩士班1年1班
Lecturer	李得勝	Full or Part-time	專任
Required / Credit	Optinal / 3	Graduate Class	NO
Time / Place	(<u></u>)34 / H367 (<u></u>)4 / H367	Language	Chinese

Introduction

Familiar with the principles of X-ray diffraction, X-ray diffraction structural analysis of operating and Materials

Outline

- One. based on principles of articles:
- 1.X-ray characteristics and detection (CH4)
- 2. free radiation protection (s)
- 3. Basic crystallography (CH1)
- 4. crystal geometry and projection (CH2)
- 5. inverted coordinate and reciprocal lattice (CH3)
- 6.X-ray scattering and diffraction (CH5)

Second, X spectrometer analysis of the basic principles and structure of articles:

- 1. of the diffraction factor (CH7, 8)
- 2. single crystal diffraction (CH9)
- 3. powder diffraction (CH10, 12)
- Third, the practice articles:
- 1. -2 powder diffraction (data paper)
- 2. Film -2 diffraction (data paper)
- 3. superlattice (data paper)
- 4. angle diffraction (data paper)
- 5. lattice stress analysis (data paper)

Prerequisite

Background knowledge required for this course as the basic electromagnetism, modern physics. There are good solid-state physics, but not absolutely necessary